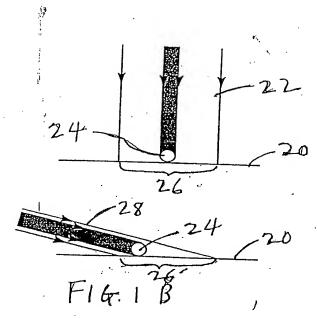
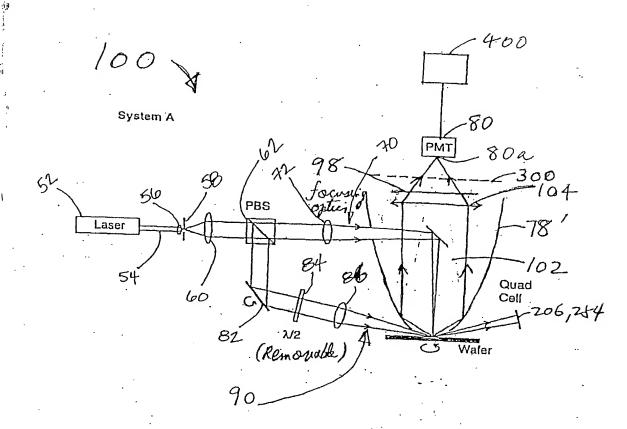
F16.1A



F19-10
28'
24'
30

F19.2+



()

F/6.2B

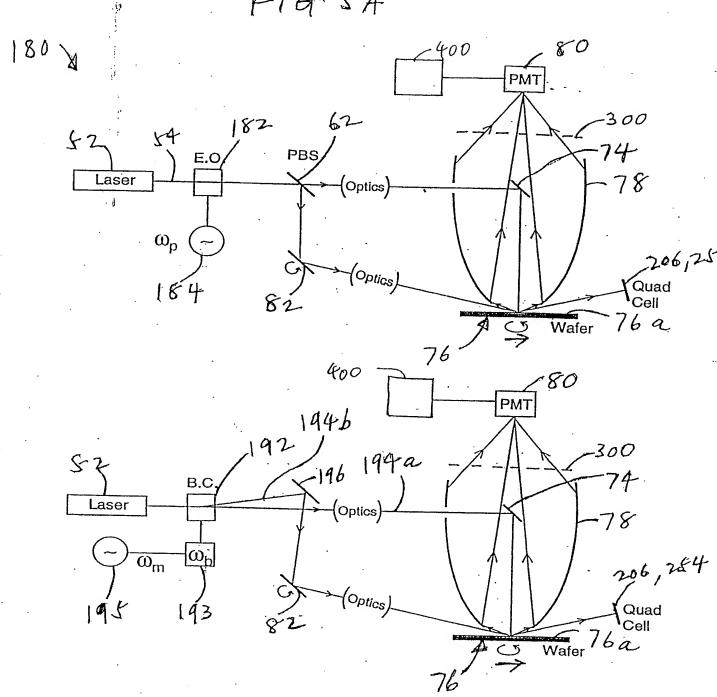
90a offset 120 F16. 3

150 400 80(1) PMT, Z, 80(>) 5,8 162 beam Splitter Pinhole 164 70' 74 -78 -164a  $\lambda_1, \lambda_2$ Laser Quad Cell SAWater 76a

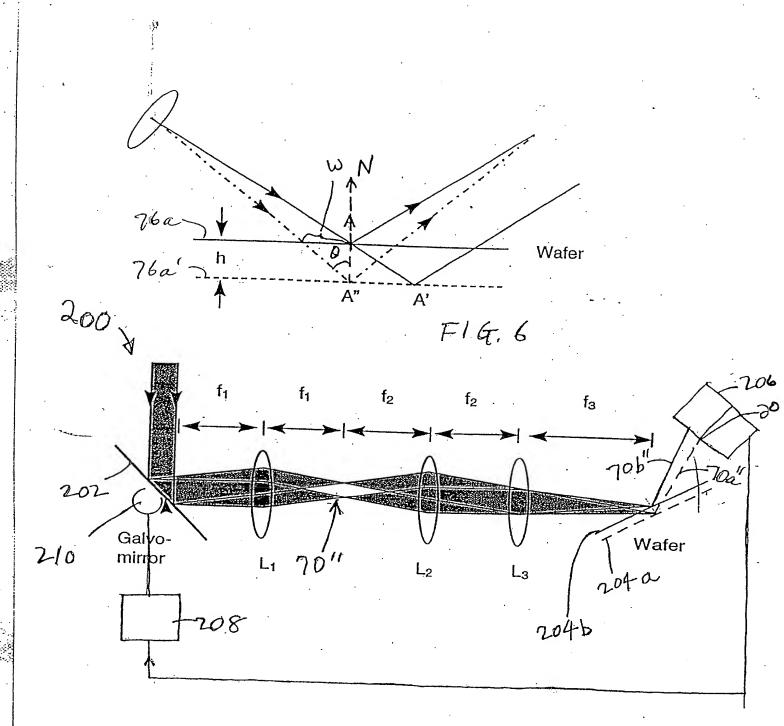
F14.4

( )

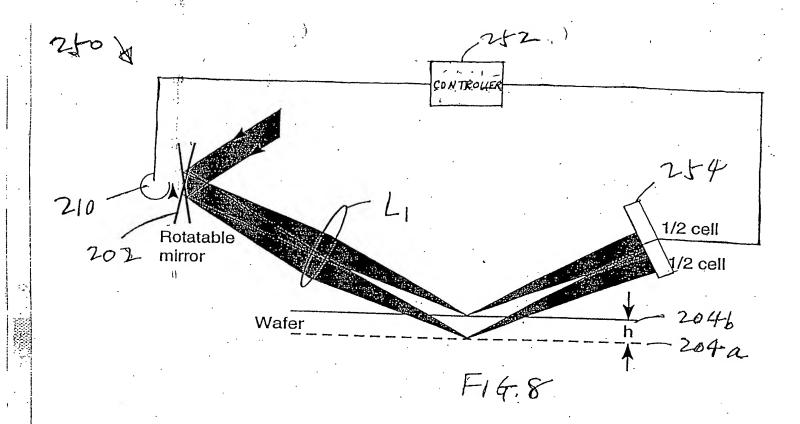
## F16 5A



F14.5B



F14.7

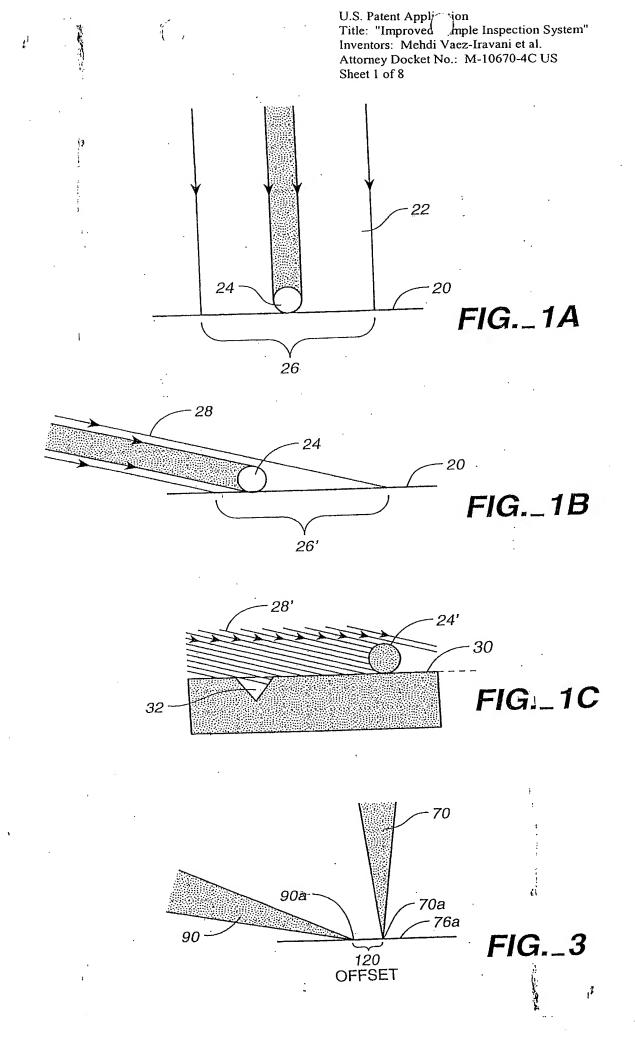


F16, 96
F16, 9B
F16, 9D
F16, 9F
F16, 9B
F16, 9D
F16, 9F

350 354 F16. 10A

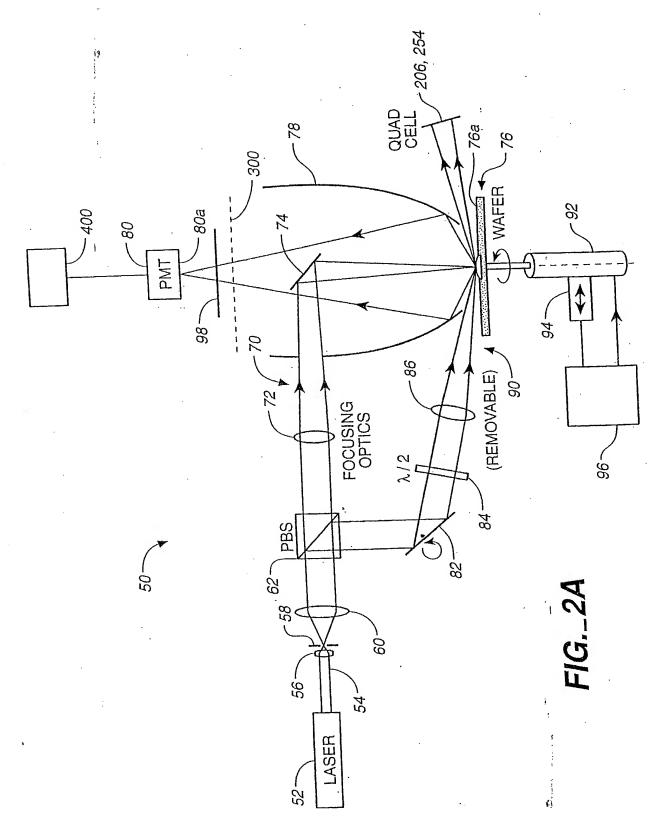
354 354 354 (i+i)
354 360

Flat OB rogrammable filter



U.S. Patent Applicion
Title: "Improved apple Inspection System"
Inventors: Mehdi Vaez-Iravani et al.
Attorney Docket No.: M-10670-4C US
Sheet 2 of 8

,7

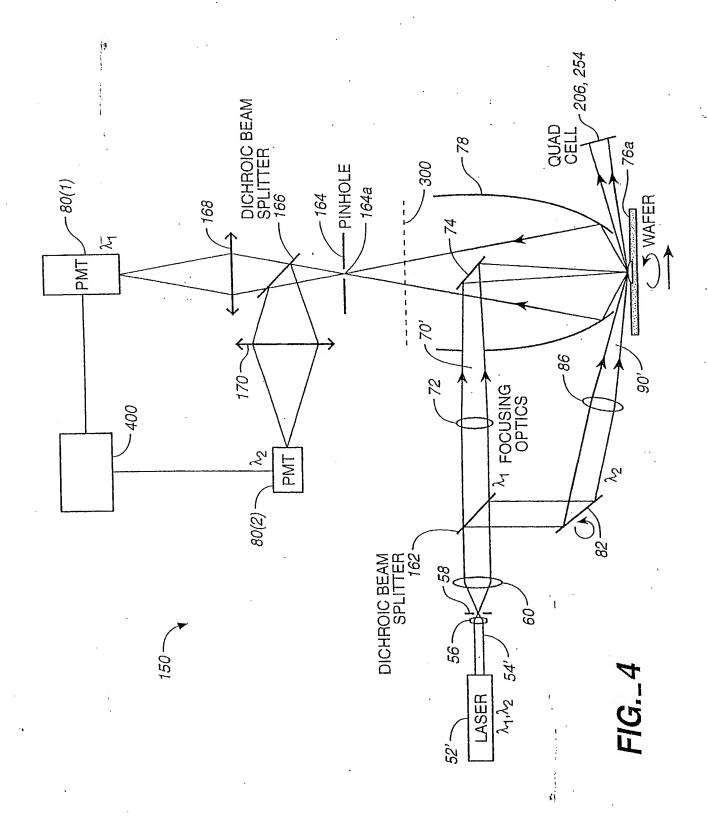


U.S. Patent Appl jon
Title: "Improved Sample Inspection System"
Inventors: Mehdi Vaez-Iravani et al. Attorney Docket No.: M-10670-4C US Sheet 3 of 8 QUAD 80a 80 PMT 98 (REMOVABLE) FOCUSING OPTICS 7,5 2 82-.79 -99 54-LASER

U.S. Patent Appli jon
Title: "Improved Jample Inspection System"
Inventors: Mehdi Vaez-Iravani et al.
Attorney Docket No.: M-10670-4C US

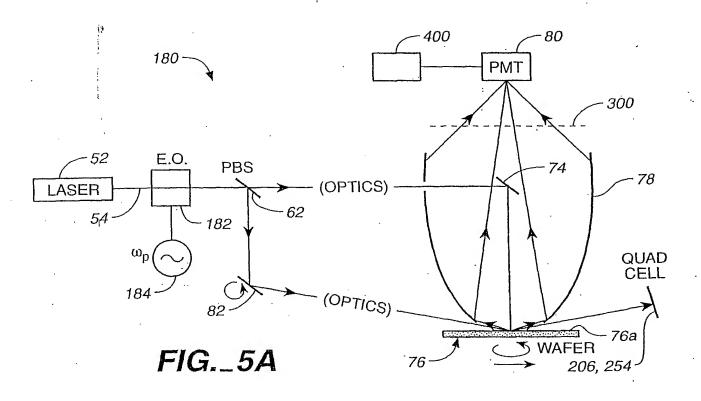
 $i^{\dagger}$ 

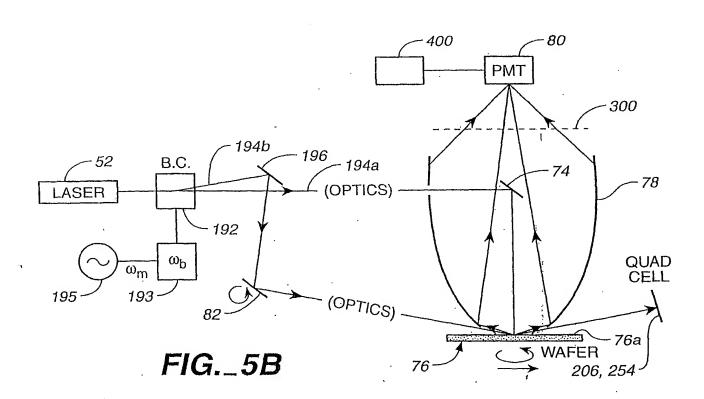
Sheet 4 of 8



U.S. Patent Applicing
Title: "Improved Sample Inspection System"
Inventors: Mehdi Vaez-Iravani et al.
Attorney Docket No.: M-10670-4C US

Sheet 5 of 8





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U.S. Patent Applign n Title: "Improved Lample Inspection System" Inventors: Mehdi Vaez-Iravani et al. Attorney Docket No.: M-10670-4C US

Sheet 6 of 8

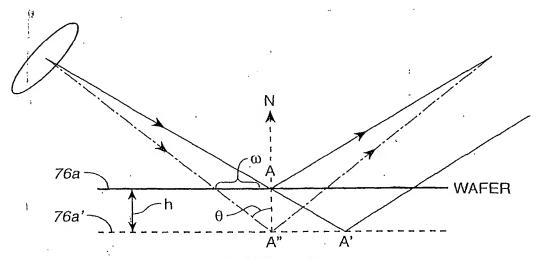


FIG.\_6

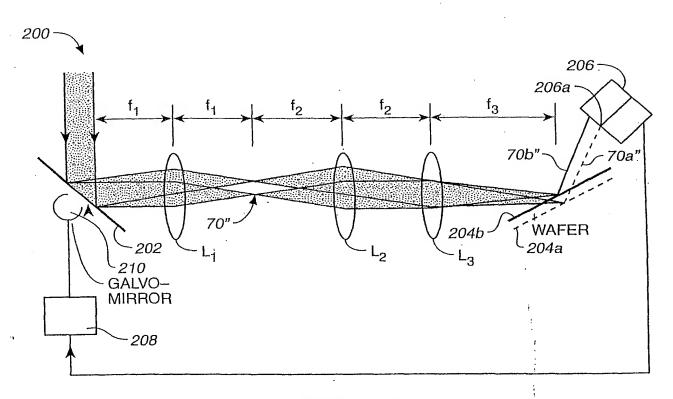
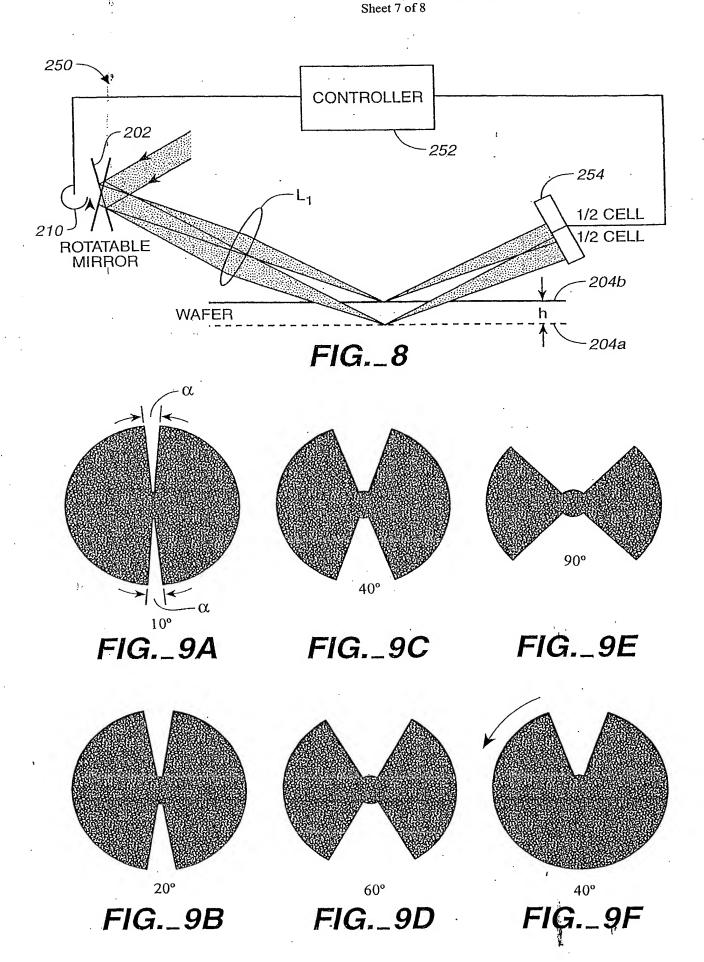


FIG.\_7

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U.S. Patent Application of Title: "Improved Laple Inspection System" Inventors: Mehdi Vaez-Iravani et al. Attorney Docket No.: M-10670-4C US



U.S. Patent Appli pn
Title: "Improved apple Inspection System"
Inventors: Mehdi Vaez-Iravani et al.

Attorney Docket No.: M-10670-4C US

Sheet 8 of 8

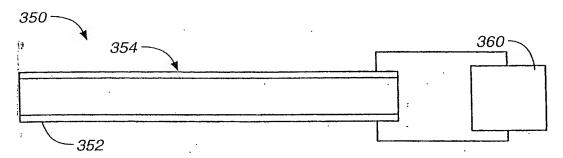


FIG.\_10A

